



High Speed Super Low Power SRAM

256k Word By 8 bit

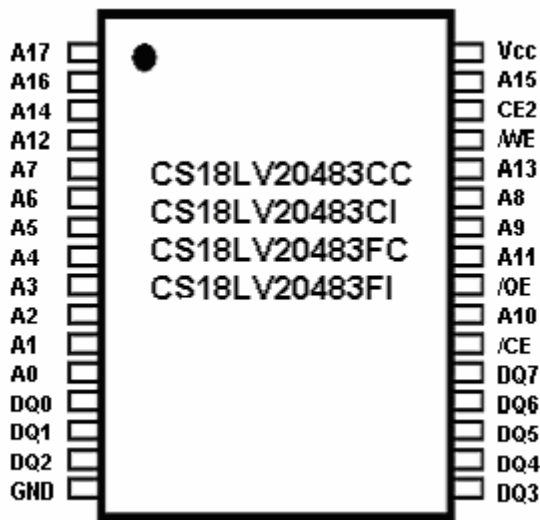
CS18LV20483

■ Product Family

Part No.	Operating Temp	Vcc. Range	Speed (ns)	Standby (Typ.)	Package Type
CS18LV20483CC	0~70°C	2.7~3.6	55/70	0.15 uA (Vcc = 3.3V)	32 SOP
CS18LV20483DC					32 STSOP
CS18LV20483EC					32 TSOP (I)
CS18LV20483FC					32 TSOP (II)
CS18LV20483KC					36 CSP -0608
Part No.	Operating Temp	Vcc. Range	Speed (ns)	Standby (Typ.)	Package Type
CS18LV20483CI	-40~85°C	2.7~3.6	55/70	0.30 uA (Vcc= 3.3V)	32 SOP
CS18LV20483DI					32 STSOP
CS18LV20483EI					32 TSOP (I)
CS18LV20483FI					32 TSOP (II)
CS18LV20483KI					36 CSP-0608

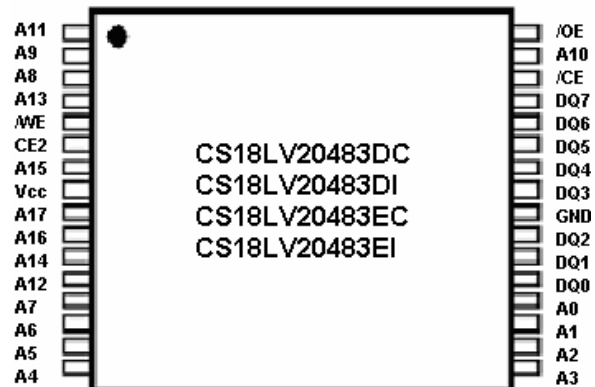
Note: Green package part no, sees order information.

■ PIN CONFIGURATIONS



32 SOP 450 mil

32 TSOP(II) 400 mil



32 STSOP 8x13.4mm

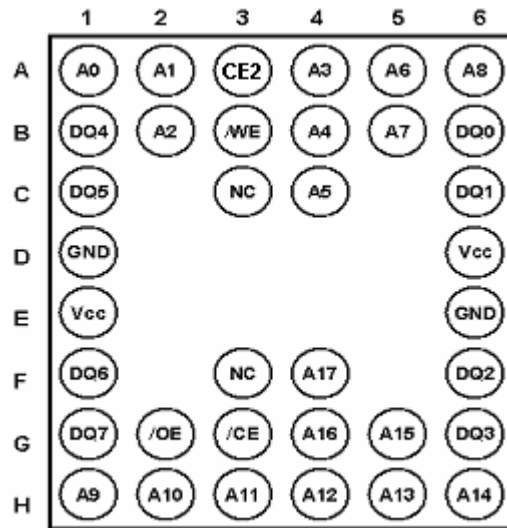
32 TSOP(I) 8x20mm



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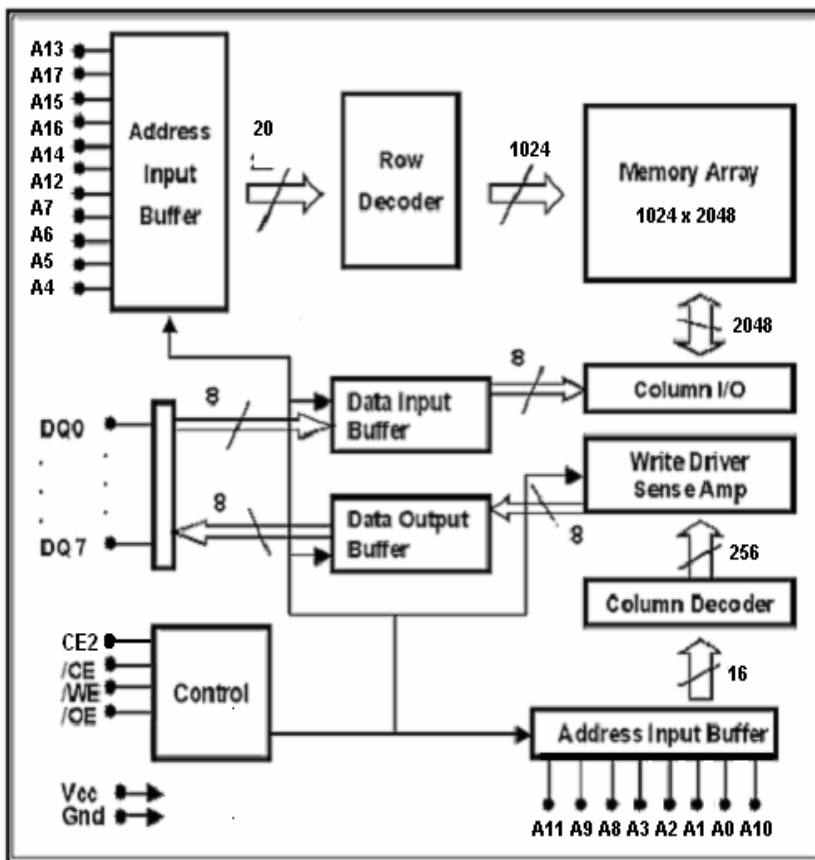
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36 BGA 6x8 mm

■ BLOCK DIAGRAM





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■ PIN DESCRIPTIONS

Name	Function
A0-A17 Address Input	These 18 address inputs select one of the 262,144 x 8-bit words in the RAM.
/CE Chip Enable Input, CE2 Chip Enable 2 Input	/CE is active LOW and CE2 is active HIGH. Both chip enables must be active when data read from or write to the device. If either chip enable is not active, the device is deselected and is in a standby power mode. The DQ pins will be in the high impedance state when the device is deselected.
/WE Write Enable Input	The write enable input is active LOW and controls read and write operations. With the chip selected, when /WE is HIGH and /OE is LOW, output data will be present on the DQ pins; when /WE is LOW, the data present on the DQ pins will be written into the selected memory location.
/OE Output Enable Input	The output enable input is active LOW. If the output enable is active while the chip is selected and the write enable is inactive, data will be present on the DQ pins and they will be enabled. The DQ pins will be in the high impedance state when /OE is inactive.
DQ0-DQ7 Data Input/Output Ports	These 8 bi-directional ports are used to read data from or write data into the RAM.
Vcc	Power Supply
Gnd	Ground



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■ TRUTH TABLE

MODE	/CE	CE2	/WE	/OE	DQ0~7	Vcc Current
Not Selected	H	X	X	X	High Z	I_{CCSB} , I_{CCSB1}
	X	L	X	X		
Output Disabled	L	H	H	H	High Z	I_{CC}
Read	L	H	H	L	D_{OUT}	I_{CC}
Write	L	H	L	X	D_{IN}	I_{CC}

■ ABSOLUTE MAXIMUM RATINGS (1)

Symbol	Parameter	Rating	Unit
V_{TERM}	Terminal Voltage with Respect to GND	-0.5 to $V_{CC}+0.5$	V
T_{BIAS}	Temperature Under Bias	-40 to +125	°C
T_{STG}	Storage Temperature	-60 to +150	°C
P_T	Power Dissipation	1.0	W
I_{OUT}	DC Output Current	20	mA

Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.



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■ DC ELECTRICAL CHARACTERISTICS (TA = 0 to +70°C, Vcc = 3.0V)

Parameter Name	Parameter	Test Conduction	MIN	TYP ⁽¹⁾	MAX	Unit
V _{IL}	Guaranteed Input Low Voltage ⁽²⁾		-0.5		0.8	V
V _{IH}	Guaranteed Input High Voltage ⁽²⁾		2.0		V _{CC} +0.2	V
I _{IL}	Input Leakage Current	V _{CC} =MAX, V _{IN} =0 to V _{CC}			1	uA
I _{OL}	Output Leakage Current	V _{CC} =MAX, /CE=V _{IN} , or /OE=V _{IN} , V _{IO} =0V to V _{CC}			1	uA
V _{OL}	Output Low Voltage	V _{CC} =MAX, I _{OL} = 2mA			0.4	V
V _{OH}	Output High Voltage	V _{CC} =MIN, I _{OH} = -1mA	2.4			V
I _{CC}	Operating Power Supply Current	/CE=V _{IL} or CE2=V _{IH} , I _{DQ} =0mA, F=F _{MAX} ⁽³⁾			25	mA
I _{CCSB}	Standby Supply - TTL	/CE=V _{IH} or CE2=V _{IL} , I _{DQ} =0mA, F=F _{MAX} ⁽³⁾			1	mA
I _{CCSB1}	Standby Current -CMOS	/CE ≥ V _{CC} -0.2V, CE2 ≤ 0.2V, V _{IN} ≥ V _{CC} -0.2V or V _{IN} ≤ 0.2V			3	uA

1. Typical characteristics are at TA = 25°C.
2. These are absolute values with respect to device ground and all overshoots due to system or tester noise are included.
3. F_{max} = 1/t_{RC}.

■ OPERATING RANGE

Range	Ambient Temperature	Vcc
Commercial	0~70°C	2.7V ~ 3.6V
Industrial	-40~85°C	2.7V ~ 3.6V

■ DATA RETENTION CHARACTERISTICS ($T_A = 0$ to $+70^\circ\text{C}$, $V_{CC} = 3.0\text{V}$)

Parameter Name	Parameter	Test Conduction	MIN	TYP ⁽¹⁾	MAX	Unit
V_{RD}	V_{CC} for Data Retention	$/CE \geq V_{CC}-0.2\text{V}$, $CE2 \leq 0.2\text{V}$, $V_{IN} \geq V_{CC}-0.2\text{V}$ or $V_{IN} \leq 0.2\text{V}$	1.5			V
I_{CCDR}	Data Retention Current	$/CE \geq V_{CC}-0.2\text{V}$, $CE2 \leq 0.2\text{V}$, $V_{IN} \geq V_{CC}-0.2\text{V}$ or $V_{IN} \leq 0.2\text{V}$		0.1	1	μA
T_{CDR}	Chip Deselect to Data Retention Time	See Retention Waveform	0			ns
t_R	Operation Recovery Time		t_{RC} (2)			ns

1. $V_{CC} = 3.0\text{V}$, $T_A = +25^\circ\text{C}$.

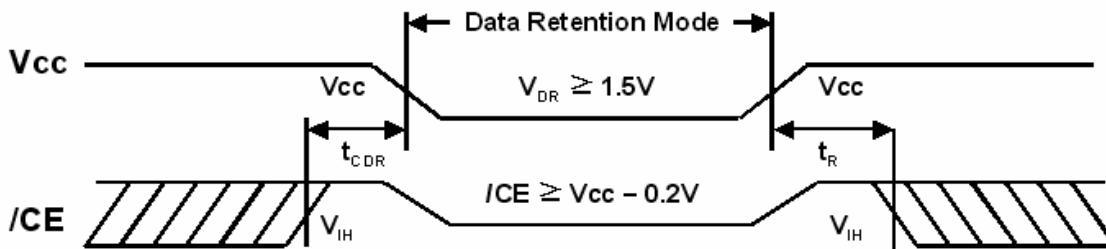
2. = Read Cycle Time.

■ CAPACITANCE ⁽¹⁾ ($T_A = 25^\circ\text{C}$, $f = 1.0\text{ MHz}$)

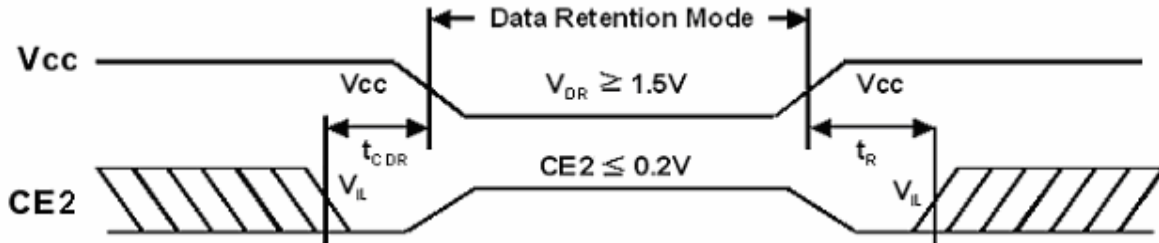
Symbol	Parameter	Conditions	MAX.	Unit
C_{IN}	Input Capacitance	$V_{IN}=0\text{V}$	10	pF
C_{DQ}	Input/Output Capacitance	$V_{IO}=0\text{V}$	10	pF

1. This parameter is guaranteed and not tested.

■ LOW V_{CC} DATA RETENTION WAVEFORM (1) ($/CE$ Controlled)



■ LOW Vcc DATA RETENTION WAVEFORM (2) (CE2 Controlled)



■ AC TEST CONDITIONS

Input Pulse Levels	Vcc/0V
Input Rise and Fall Times	5ns
Input and Output	
Timing Reference Level	0.5Vcc

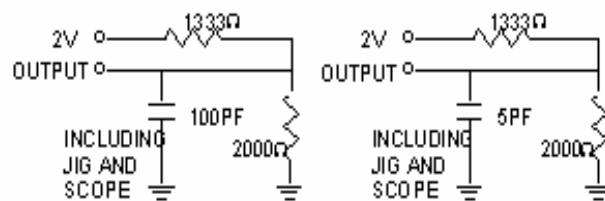


FIGURE 1A

FIGURE 1B



THEVENIN EQUIVALENT

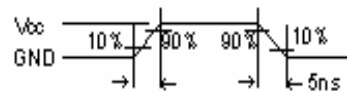


FIGURE 2

■ KEY TO SWITCHING WAVEFORMS

WAVEFORM	INPUTS	OUTPUTS
	Must be standby	Must be standby
	May change for H to L	Will be change from H to L
	May change for L to H	May change for L to H
	Don't care any change permitted	Change state unknown
	Does not apply	Center line is high impedance "OFF" state



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■ AC ELECTRICAL CHARACTERISTICS (TA = 0 to + 70°C , Vcc = 3.3V)

< READ CYCLE >

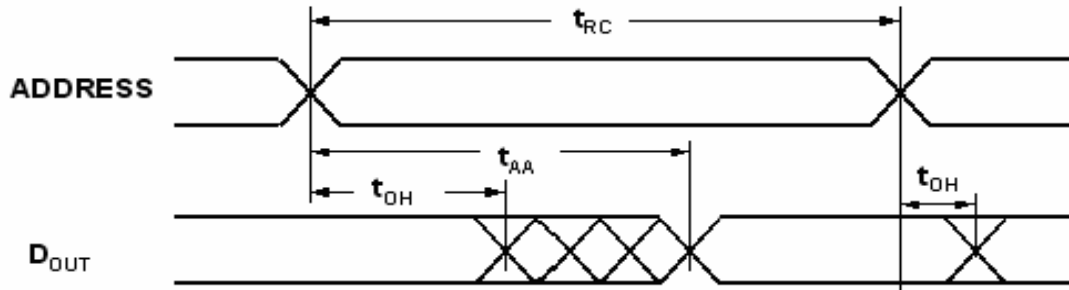
JEDEC Parameter Name	Parameter Name	Description	55		-70		Unit
			MIN	MAX	MIN	MAX	
t _{AVAX}	t _{RC}	Read Cycle Time	55		70		ns
t _{AVQV}	t _{AA}	Address Access Time		55		70	ns
t _{ELQV}	t _{ACS}	Chip Select Access Time (/CE)		55		70	ns
t _{E2HQV}	t _{ACS2}	Chip Select Access Time (CE2)		55		70	ns
t _{GLQV}	t _{OE}	Output Enable to Output Valid		25		35	ns
t _{ELQX}	t _{CLZ}	Chip Select to Output Low Z (/CE)	10		10		ns
t _{E2HQX}	t _{CLZ2}	Chip Select to Output Low Z (CE2)	10		10		ns
t _{GLQX}	t _{OLZ}	Output Enable to Output in Low Z	5		5		ns
t _{EHQZ}	t _{CHZ}	Chip Deselect to Output in High Z (/CE)	0	25	0	30	ns
t _{E2LQZ}	t _{CHZ2}	Chip Deselect to Output in High Z (CE2)	0	25	0	30	ns
t _{GHQZ}	t _{OHZ}	Output Disable to Output in High Z	0	25	0	30	ns
t _{AXOX}	t _{OH}	Out Disable to Address Change	10		10		ns

NOTES:

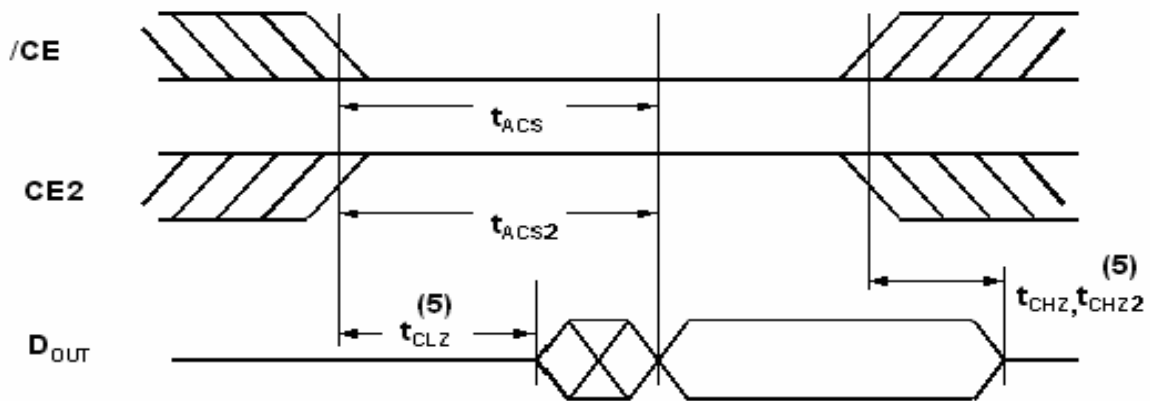
1. /WE is high in read Cycle.
2. Device is continuously selected when /CE = V_{IL} and CE2=V_{IH}.
3. Address valid prior to or coincident with /CE transition low and /or CE2 transition high.
4. /OE = V_{IL}.
5. Transition is measured ±500mV from steady state with C_L = 5pF as shown in Figure 1B. The parameter is guaranteed but not 100% tested.

SWITCHING WAVEFORMS (READ CYCLE)

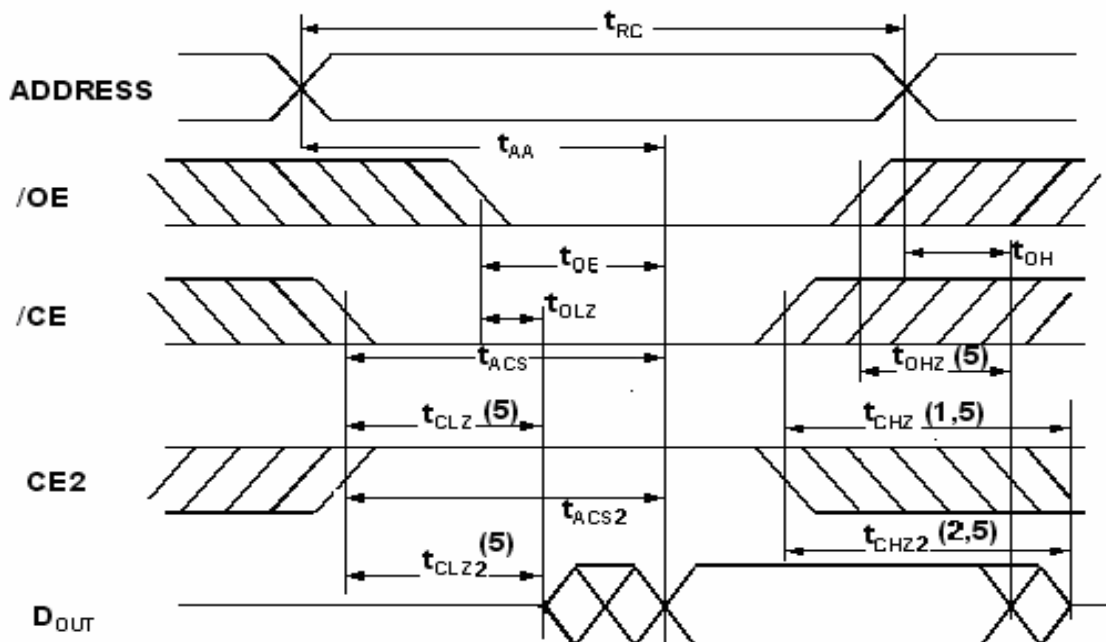
READ CYCLE 1 (1,2,4)



READ CYCLE 2 (1,3,4)



READ CYCLE 3 (1,4)





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■ AC ELECTRICAL CHARACTERISTICS (TA = 0 to + 70°C , Vcc = 3.3V)

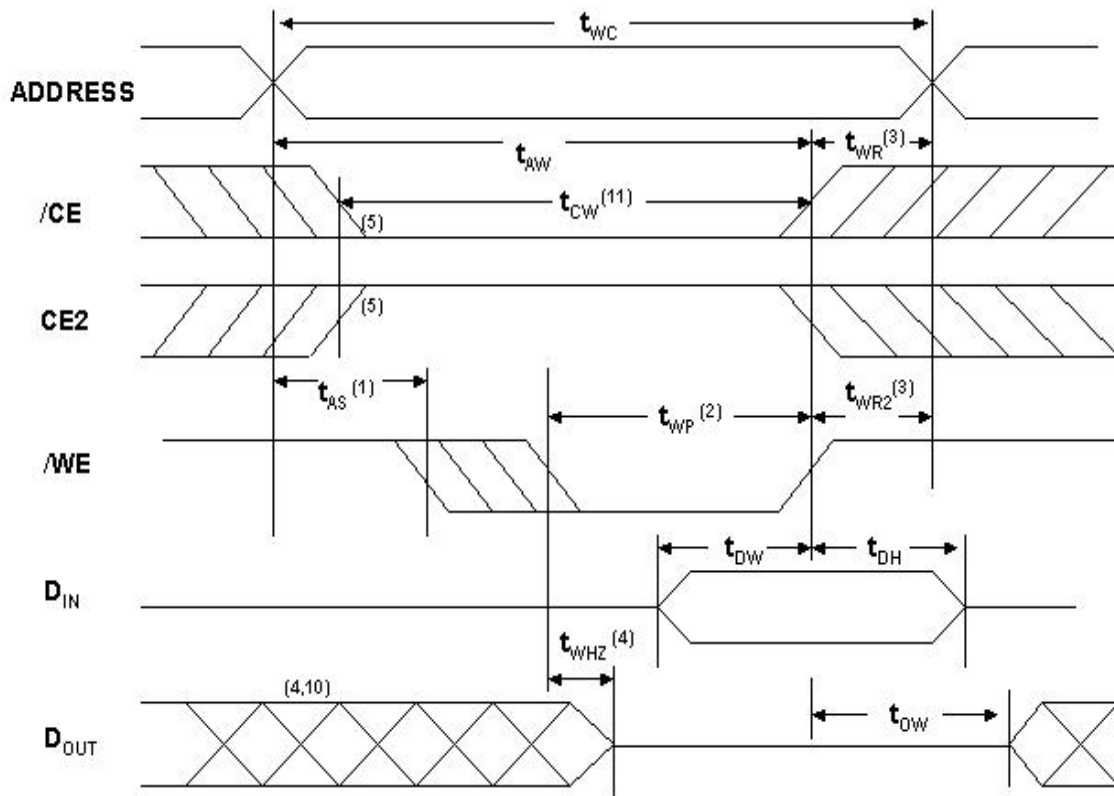
< WRITE CYCLE >

JEDEC Parameter Name	Parameter Name	Description	- 55		-70		Unit
			MIN	MAX	MIN	MAX	
t _{AVAX}	t _{wc}	Write Cycle Time	55		70		ns
t _{E1LWH}	t _{cw}	Chip Select to End of Write	50		60		ns
t _{AVWL}	t _{AS}	Address Setup Time	0		0		ns
t _{AVWH}	t _{AW}	Address Valid to End of Write	55		60		ns
t _{WLWH}	t _{WP}	Write Pulse Width	45		50		ns
t _{WHAX}	t _{WR}	Write Recovery Time (/CE, /WE)	0		0		ns
t _{E2LAX}	t _{WR2}	Write Recovery Time (CE2)	0		0		ns
t _{WLQZ}	t _{WHZ}	Write to Output in High Z		20		25	ns
t _{DVWH}	t _{DW}	Data to Write Time Overlap	25		30		ns
t _{WHDX}	t _{DH}	Data Hold from Write Time	0		0		ns
t _{WHOX}	t _{ow}	End of Write to Output Active	5		10		ns

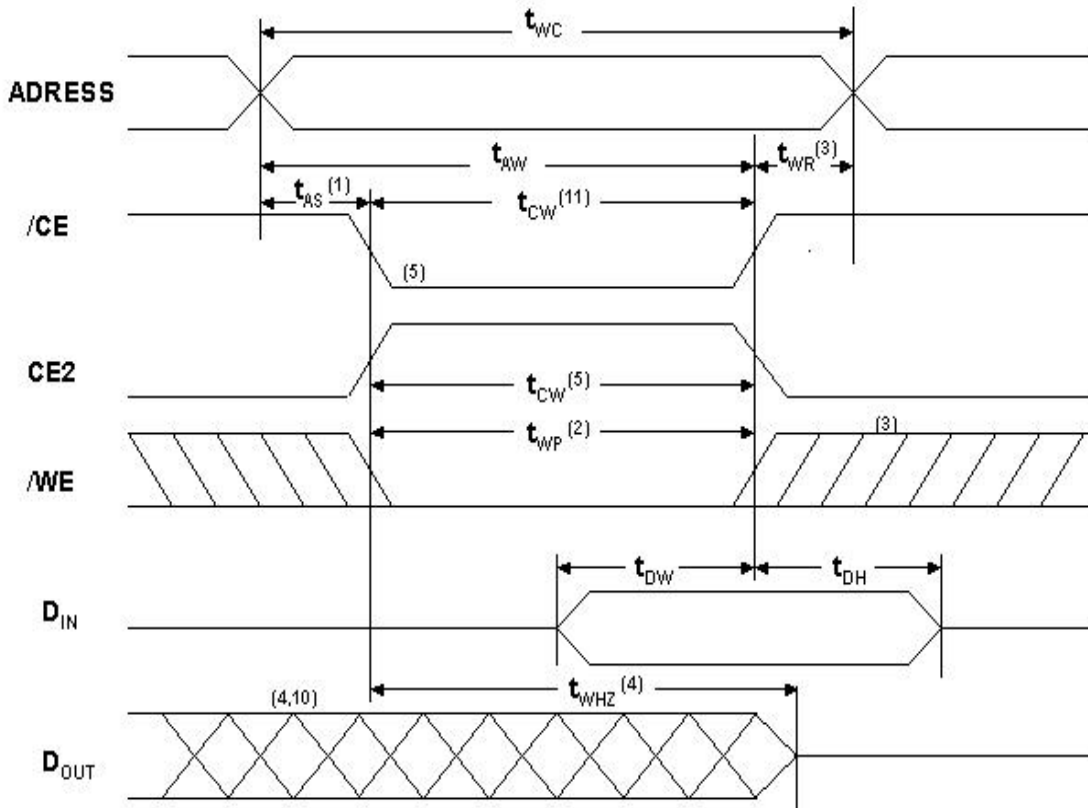


SWITCHING WAVEFORMS (WRITE CYCLE)

WRITE CYCLE 1 (Write Enable Controlled)



WRITE CYCLE 2 (Chip Enable Controlled)



NOTES:

1. T_{AS} is measured from the address valid to the beginning of write.
2. The internal write time of the memory is defined by the overlap of /CE and CE2 active and /WE low. All signals must be active to initiate a write and any one signal can terminate a write by going inactive. The data input setup and hold timing should be referenced to the second transition edge of the signal that terminates the write.
3. T_{WR} is measured from the earlier of /CE or /WE going high or CE2 going low at the end of write cycle.
4. During this period, DQ pins are in the output state so that the input signals of opposite



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phase to the outputs must not be applied.

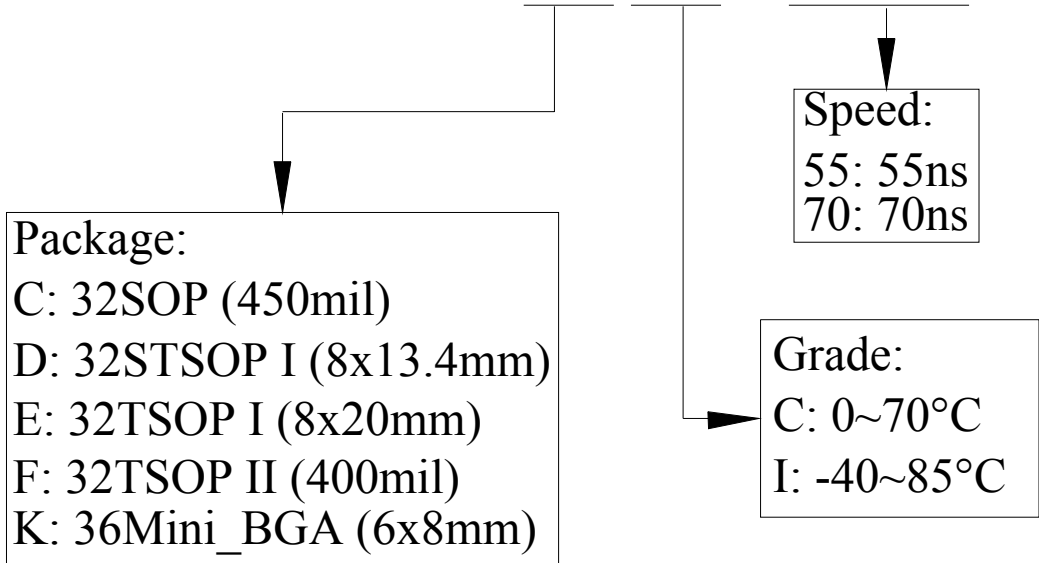
5. If the /CE low transition or CE2 high transition occurs simultaneously with the /WE low transitions or after the /WE transition, output remain in a high impedance state.
6. /OE is continuously low ($/OE = V_{IL}$).
7. D_{OUT} is the same phase of write data of this write cycle.
8. D_{OUT} is the read data of next address.
9. If /CE is low and CE2 is high during this period, DQ pins are in the output state. Then the data input signals of opposite phase to the outputs must not be applied to them.
10. Transition is measured $\pm 500\text{mV}$ from steady state with $C_L = 5\text{pF}$ as shown in Figure 1B. The parameter is guaranteed but not 100% tested.
11. T_{CW} is measured from the later of /CE going low or CD2 going high to the end of write.



ORDER INFORMATION

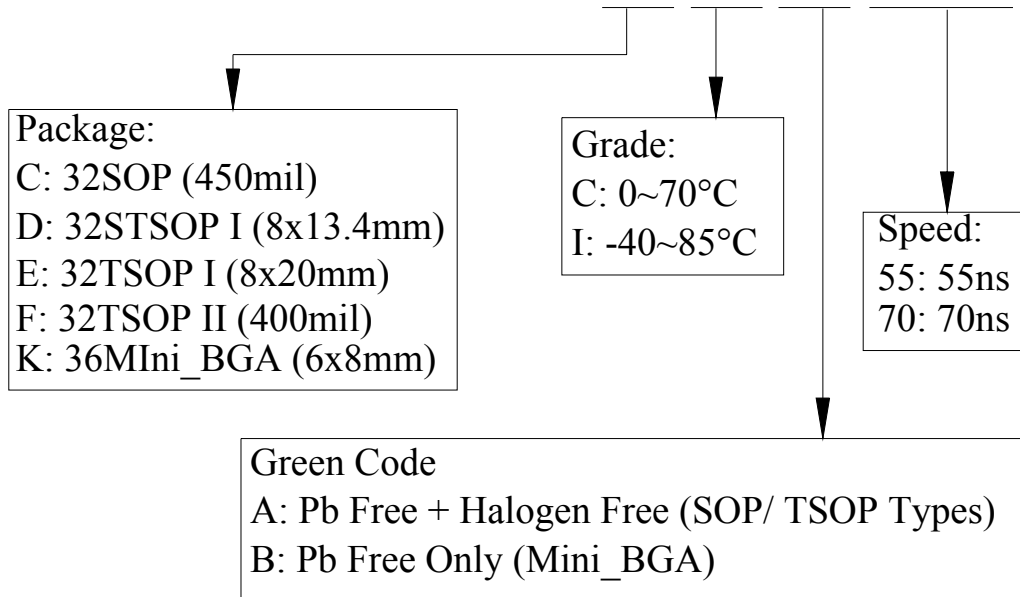
1. NON-GREEN PACKAGE:

CS18LV20483 X X - XX



2. GREEN PACKAGE:

CS18LV20483 X X X XX





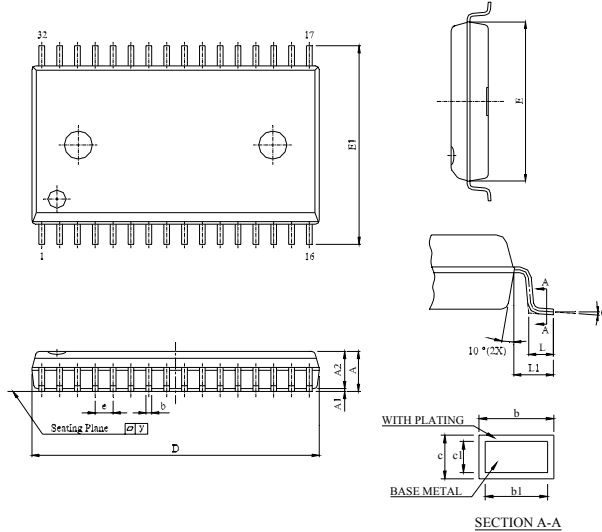
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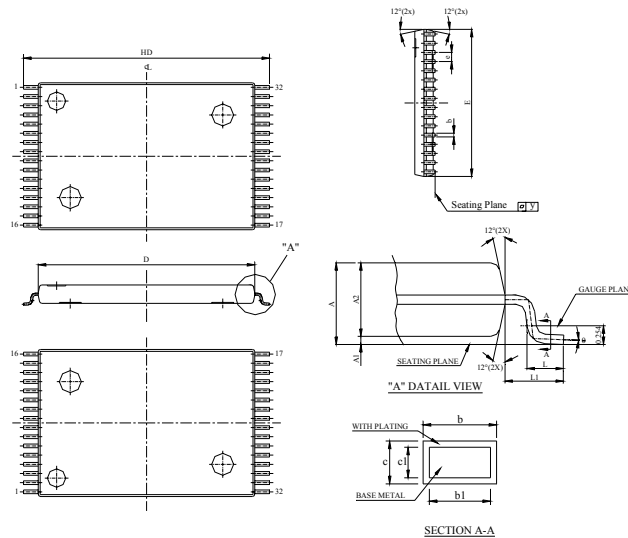
PACKAGE DIMENSIONS

- 32 pin SOP (450 mil) :



SYMBOL UNIT	A	A1	A2	b	b1	c	c1	D	E	E1	e	L	L1	y	Ø	
mm	Min.	2.645	0.102	2.540	0.35	0.35	0.15	0.15	20.320	11.176	13.792	1.118	0.584	1.194	-	0°
	Nom.	2.821	0.229	2.680	-	-	-	-	20.447	11.303	14.097	1.270	0.834	1.397	-	-
	Max.	2.997	0.356	2.820	0.50	0.46	0.32	0.28	20.574	11.430	14.402	1.422	1.084	1.600	0.1	10°
inch	Min.	0.104	0.004	0.1000	0.014	0.014	0.006	0.006	0.800	0.440	0.543	0.044	0.023	0.047	-	0°
	Nom.	0.111	0.009	0.1055	-	-	-	-	0.805	0.445	0.555	0.050	0.033	0.055	-	-
	Max.	0.118	0.014	0.1110	0.020	0.018	0.012	0.011	0.810	0.450	0.567	0.056	0.043	0.063	0.004	10°

- 32 pin sTOSOP (8x13.4 mm) :



SYMBOL UNIT	A	A1	A2	b	b1	c	c1	D	E	e	HD	L	L1	y	Ø	
mm	Min.	1.00	0.05	0.95	0.17	0.17	0.10	0.10	11.70	7.90	0.40	13.20	0.40	0.70	-	0°
	Nom.	1.10	0.10	1.00	0.22	0.20	-	-	11.80	8.00	0.50	13.40	0.50	0.80	-	-
	Max.	1.20	0.15	1.05	0.27	0.23	0.21	0.16	11.90	8.10	0.60	13.60	0.70	0.90	0.1	8°
inch	Min.	0.0393	0.002	0.037	0.007	0.007	0.004	0.004	0.461	0.311	0.016	0.520	0.0157	0.0275	-	0°
	Nom.	0.0433	0.004	0.039	0.009	0.008	-	-	0.465	0.315	0.020	0.528	0.0197	0.0315	-	-
	Max.	0.0473	0.006	0.041	0.011	0.009	0.008	0.006	0.469	0.319	0.024	0.536	0.0277	0.0355	0.004	8°

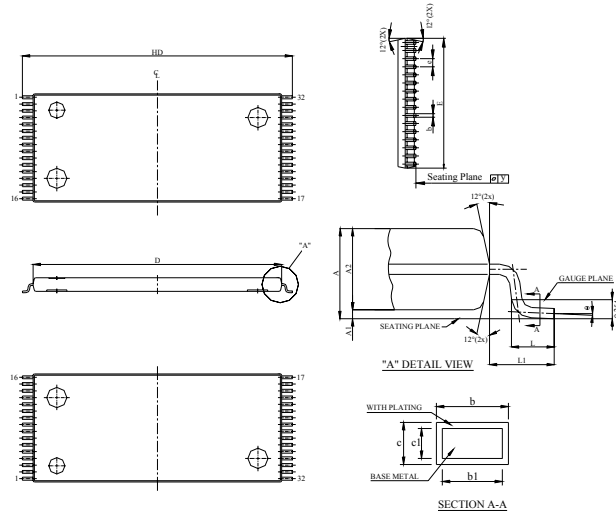


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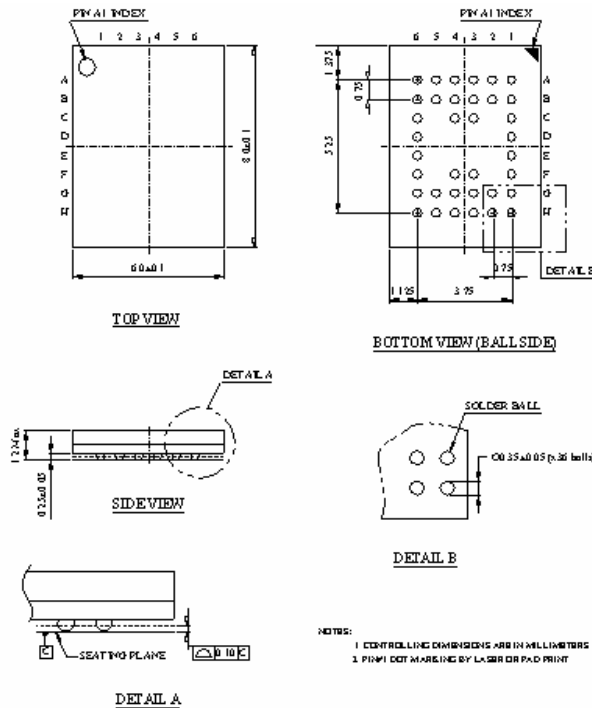
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- 32 pin TSOP (I) (8x20 mm)



SYMBOL UNIT	A		A1		A2		b		b1		c		c1		D	E	e	HD	L	L1	y	Ø
	mm	Min.	1.00	0.05	0.95	0.17	0.17	0.10	0.10	18.30	7.90	0.40	19.80	0.40	0.70	-	-	0°				
	Nom.	1.10	0.10	1.00	0.22	0.20	-	-	18.40	8.00	0.50	20.00	0.50	0.80	-	-						
	Max.	1.20	0.15	1.05	0.27	0.23	0.21	0.16	18.50	8.10	0.60	20.20	0.70	0.90	0.1	8°						
inch	Min.	0.0393	0.002	0.037	0.007	0.007	0.004	0.004	0.720	0.311	0.016	0.779	0.0157	0.0275	-	0°						
	Nom.	0.0433	0.004	0.039	0.009	0.008	-	-	0.724	0.315	0.020	0.787	0.0197	0.0315	-							
	Max.	0.0473	0.006	0.041	0.011	0.009	0.008	0.006	0.728	0.319	0.024	0.795	0.0277	0.0355	0.004	8°						

- 36 pin BGA (6x8 mm)



NOTES:
 1. CONTROLLING DIMENSIONS ARE IN MILLIMETERS
 2. PINS 1 DET MARELINE BY LASER OR PAD PRINT